

CIRCUIT PARAMETER TEST DATA - DIGITAL

1. CCSD	2. TYPE TEST	3. START TIME (DTG)	4. END TIME (DTG)
5. PARAMETER CODE	6. DATA RATE	7. TYPE INTERFACE	8. TYPE SYNC/CLOCK SOURCE
9. TYPE SIGNAL/CODING	10. TEST PATTERN	11. BLOCK SIZE	
12. LOCAL STATION TEST ADMINISTRATOR		13. DISTANT END TEST ADMINISTRATOR	

TEST SPECIFICATIONS		TEST RESULTS		
TYPE	SPECIFICATION	TYPE	LOCAL	DISTANT END
14. BIT ERROR RATE	1 X 10 -	Total Errors		
		Error Rate		
15. % ERROR FREE SECONDS	_____ %	Errored Seconds		
		% EFS		
16. SEVERELY ERRORED SECONDS (SES) %	_____ %	SES		
		% SES		
17. % DEGRADED MINUTES	_____ %	Degraded Minutes		
		% Degraded Minutes		
18. RESIDUAL BER	1 X 10 -	Total Errors		
		Error Rate		
19. AVAILABILITY	_____ %	Unavailable Seconds		
		% Unavailable Seconds		
20. LOSS OF BIT COUNT INTEGRITY (LBCI)	< _____	Pattern/Data Loss		
		Clock Loss		
21. DELAY	milli-seconds: _____	Delay		
22. TIMING ERRORS	< _____	Pattern Slips		
		Clock Slips		
23. BI-POLAR VIOLATIONS (BPV)	< _____	Total BPV		
		Average BPV Rate		
24. FRAME ERRORS	< _____	Total Frame Errors		
		Frame Error Rate		
25. CYCLIC REDUNDANCY CHECK (CRC) ERRORS	< _____	Total CRC Errors		
		Average CRC		
26. PARITY ERRORS		Total Parity Errors		
		Average Parity Errors		

27. REMARKS	<input type="checkbox"/>	PASS	<input type="checkbox"/>	FAIL

PERFORM ALL TESTS SIMULTANEOUSLY WHENEVER POSSIBLE.	28. SIGNATURE OF TEST ADMINISTRATOR
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**INSTRUCTIONS FOR COMPLETING DD FORM 1697-1,
CIRCUIT PARAMETER TEST DATA - DIGITAL**

Item 1 - Enter the Command Communication Service Designator (CCSD) of the link, trunk, or circuit being tested. (NOTE: for the rest of the instructions, the term "circuit" will be used generically to refer to either the link, trunk, or circuit being tested.)

Item 2. Enter the type of test being performed: Initial Test and Acceptance or Out-of-Service QC.

Item 3 - Enter the date and time the test began.

Item 4 - Enter the date and time the test was completed.

Item 5 - Enter the parameter code of the circuit under test (found in the TSO item 2.(f)).

Item 6 - Enter the data rate of the circuit under test (found in the TSO item 2.(l)).

Item 7 - Enter the type of interface used to connect the test set to the circuit being tested.

Item 8 - Enter the type of synchronization used on the test set and the source of the clock timing.

Item 9 - Enter the type of signal (NRZ, AMI, etc.) and coding (D4, ESF, etc.) of the circuit under test.

Item 10 - Enter the type of test pattern used (configured on the test set).

Item 11 - Enter the size of the data block the test set is configured for.

Item 12 - Enter the name of the test administrator at the local facility.

Item 13 - Enter the name of the test administrator at the distant end facility.

Items 14 - 26:

Under the Test Specification column, insert the specification identified in DISAC 300-175-9, Chapter 3, which corresponds to the parameter code of the circuit under test.

Under the Test Results, Local column, record the results acquired by the test set for each type of test result by the local facility.

Under the Distant End column, record the results acquired by the test set for each type of test result by the distant end facility.

Item 27 - Enter any amplifying remarks pertinent to the test. Compare the test specifications with the results to determine if the test passed or failed. Mark the appropriate box.

Item 28 - Enter the signature of test administrator or supervisor.